


<b>Search Notes</b>  	<b>Application/Control No.</b>  10555474	<b>Applicant(s)/Patent Under Reexamination</b>  MAIER ET AL.
	<b>Examiner</b>  Jeffrey Lenihan	<b>Art Unit</b>  1765

SEARCHED			
Class	Subclass	Date	Examiner
525	191, 240	4/2/2009	/JL/

SEARCH NOTES		
Search Notes	Date	Examiner
inventor search in eDAN/PALM	4/2/2009	/JL/
see attached EAST history	4/2/2009	/JL/
updated EAST history	12/1/2009	/JL/
updated EAST search	10/1/2011	/JL/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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